

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
		Examiner Paul D Kim	Art Unit 3729	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,129,866	10-2000	Hamanaka et al.	264/1.7
	B	US-5,767,020	06-1998	Sakaguchi et al.	438/705
	C	US-5,667,700	09-1997	Rudigier et al.	216/12
	D	US-4,309,075	01-1982	Apfel et al.	359/586
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11083798 A	03-1999	Japan	NAKAMURA et al.	G01N 27/447
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"A novel flying height measurement approach for optical sliders"; Binghe Ma; Morsbach, C.; Gatzen, H.H.; Sensors, 2003. AsiaSense 2003. Asian Conference on 2003 Page(s):29 - 32.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.